

Search Notes (continued)

Application/Control No.

10/734,905

Examiner

Sun J. Lin

Applicant(s)/Patent under
Reexamination

HWANG ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	2	8/10/2006	JSL
716	16	8/10/2006	JSL
716	17	8/10/2006	JSL
716	18	8/10/2006	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	2	8/10/2006	JSL
716	18	8/10/2006	JSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	8/10/2006	JSL
IEEE	8/10/2006	JSL
GOOGLE	8/10/2006	JSL